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... at a test location when the **device under test** is not ... at an arbitrary time, without **synchronization** to a ... that are applied to the **unit under test** from affecting ...

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... R-ECT signal, and the **synchronization** symbol are ... signal is generated into the **device under test** and the ... the transverse balance of the **unit under test** and the ...

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... the features to the **unit under test** before running. ... Internet Bridge, LAN Access, **Synchronization**, Headset and ... individually to a **device under test**. This allows ...

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... programs running on the **device under test** have to ... For **synchronization** all TBes are connected to the ... The **unit under test** (microcontroller product) consists of ...

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... DUT **Device Under Test**. It is used interchangeably with UUT (**Unit Under Test**). ... and the timing of the CPU are "in synch." The **synchronization** eliminates time ...

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... communications) DUT **device under test** DVI digital ... SRCS SilkRoad Refractive **Synchronization** Communication SRL ... outline package UUT **unit under test** uV microvolt ...

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... signal generated within the **unit under test**, allowing a ... affect timing accuracy and **synchronization** throughout a ... accurately from the **device under test** to the ...
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... The feature set of the **unit-under-test** (UUT) dictates which test method to use. For the baseband BER test, the demodulated PRBS signal at the receiver ...
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... complete measurement solution. The two tools flank the input and output terminals of the **device-under-test** (DUT) as shown in Figure 1 ...
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under test (UUT), either ... is transferred out to a **device under test** to provide ...

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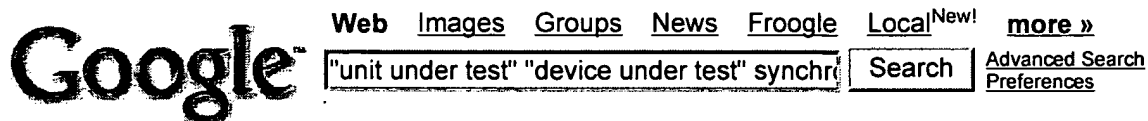
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signal c : integer range 0 to 49999; begin process(clk,rst) begin if rst='1' then c != 0; elsif (clk'event) and (clk='1') then if c=49999 then c != 0; else ...

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... DUP Data User Part. DUT **Device Under Test**. DVB Digital Video Broadcast. ... SWR Standing Wave Ratio. SYNC **Synchronization**. SYS System. ... UUT **Unit Under Test**. UV Ultraviolet ...

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... ARB A specific primitive bit sequence as defined in FC-PH BER Bit Error Rate BERT Bit Error Rate Tester BUJ Bounded Uncorrelated Jitter CDR **Clock** and Data ...

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... test), and reversed when viewed from the **device under test** (ie, modport dut). ... 5; // use busA => (posedge **clk1**). ... These are some example **synchronization** statements ...

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


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










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Killig, Ralf / Agilent Technologies, Inc., EUROPEAN PATENT APPLICATION, Nov 2004
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GAGE, Robert, B. / TERADYNE, INC., EUROPEAN PATENT, Nov 2001
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...a defect that is deleterious to **device** performance must already be measurable...the associated relative change in **device-under-test** (DUT) capacitance is negligible...saturated

trap-filling across the **device**, SIDLTS relies on trap-filling...

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...enabling the **synchronization** of the pulse...the circuit **under test**. The pulse...arriving on the **device** with 0.811m...absorbed by the **device**, two calibrated...automation of the **test** in terms of positioning, **synchronization**, and measurements...modulator, DUT: **device under test**, MO: microscope...

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...signal, and blocks for timing and **synchronization**. Software support is given through...into state O N. The block D U T (**Device Under Test**) is driven by the sinewave shaped...jjj) are satisfied, the phase **Test-Measurement-Cycles** proceeds, otherwise...

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Very Large Scale Integration (VLSI) Systems, IEEE Transactions on , Volume:

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L31	6	clk1 same clk2 same 18	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/25 10:33
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